AN78xxNSP Series

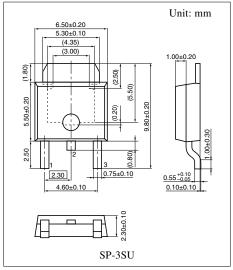
3-pin positive output voltage regulator (1 A type)

Overview

The AN78xxNSP series is a 3-pin fixed positive output type monolithic voltage regulator housed in surface mounting package. Stabilized fixed output voltage is obtained from unstable DC input voltage with using minimum external components. 9 types of fixed output voltage are available; 5 V, 6 V, 7 V, 8 V, 9 V, 10 V, 12 V, 15 V and 18 V. They can be used widely in power circuits with current capacity up to 1 A.

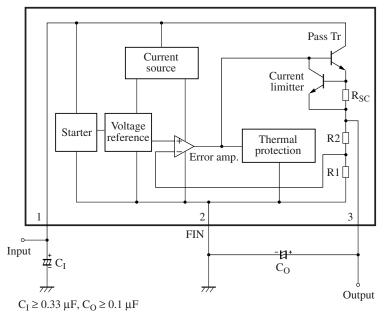
■ Features

- Output voltage: 5V,6V,7V,8V,9V,10V,12V,15V,18V
- Built-in overcurrent limit circuit
- Built-in thermal overload protection circuit
- Built-in ASO (area of safe operation) protection circuit



Note) The package of this product will be changed to lead-free type (SP-3SUA). See the new package dimensions section later of this datasheet.

■ Block Diagram



■ Pin Descriptions

| Pin No. | | Description |
|---------|--------|--------------------|
| 1 | Input | Input voltage pin |
| 2 | GND | Ground pin (FIN) |
| 3 | Output | Output voltage pin |

■ Absolute Maximum Ratings

| Parameter | Symbol | Range | Unit |
|----------------------------------|------------------|-------------|------|
| Supply voltage | V _{CC} | 35 | V |
| Supply current | I_{CC} | _ | mA |
| Power dissipation *2 | P_{D} | 364 | mW |
| Operating ambient temperature *1 | T _{opr} | -30 to +85 | °C |
| Storage temperature *1 | T_{stg} | -55 to +150 | °C |

Note) 1. *1: Except for the operating ambient temperature and storage temperature, all ratings are for $T_a = 25^{\circ}$ C.

■ Electrical Characteristics at $T_a = 25$ °C

• AN7805NSP (5 V type)

The specified condition $T_j = 25$ °C means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, $V_I = 10 \text{ V}$, $I_O = 500 \text{ mA}$, $C_I = 0.33 \mu\text{F}$ and $C_O = 0.1 \mu\text{F}$

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|---|------|-----|------|------|
| Output voltage | V _{O1} | $T_j = 25^{\circ}C$ | 4.8 | 5 | 5.2 | V |
| Output voltage tolerance | V _{O2} | $V_{I} = 8 \text{ V to } 20 \text{ V}, I_{O} = 5 \text{ mA to } 1 \text{ A}$ $T_{j} = 25^{\circ}\text{C}, P_{D} < 5 \text{ W}$ | 4.75 | _ | 5.25 | V |
| Line regulation 1 | REG _{IN1} | $V_I = 7.5 \text{ V to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 3 | 100 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 8 \text{ V to } 12 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 1 | 50 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 15 | 100 | mV |
| Load regulation 2 | REG _{L2} | $I_O = 250 \text{ mA to } 750 \text{ mA}, T_j = 25^{\circ}\text{C}$ | _ | 5.0 | 50 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 3.9 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 7.5 \text{ V to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.3 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 8 \text{ V to } 18 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 62 | _ | _ | dB |

· Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|-------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 40 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | | 2 | | V |
| Output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | _ | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25$ °C | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | | - 0.3 | | mV/°C |
| Thermal protection operating temperature | $T_{j(TH)}$ | $I_O = 5 \text{ mA}$ | | 150 | | °C |

^{*2:} The power dissipation shown is the value for the independent IC without a heat sink at $T_a = 85^{\circ}$ C. When Tj exceeds 150°C (designed value), the internal circuit cuts off the output.

^{2.} This IC is not suitable for car electronics equipment.

• AN7806NSP (6 V type)

The specified condition $T_j = 25^{\circ}C$ means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, V_I = 11 V, I_O = 500 mA, C_I = 0.33 μF and C_O = 0.1 μF

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|--|------|-----|------|------|
| Output voltage | V _{O1} | $T_j = 25$ °C | 5.75 | 6 | 6.25 | V |
| Output voltage tolerance | V _{O2} | $V_{I} = 9 \text{ V to } 21 \text{ V}, I_{O} = 5 \text{ mA to } 1 \text{ A}$ | 5.7 | _ | 6.3 | V |
| | | $T_j = 25^{\circ}C, P_D < 5 W$ | | | | |
| Line regulation 1 | REG _{IN1} | $V_I = 8.5 \text{ V to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 5 | 120 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 9 \text{ V to } 13 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 1.5 | 60 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 14 | 120 | mV |
| Load regulation 2 | REG _{L2} | $I_{O} = 250 \text{ mA to } 750 \text{ mA}, T_{j} = 25^{\circ}\text{C}$ | _ | 4.0 | 60 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 3.9 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 8.5 \text{ V to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.3 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 9 \text{ V to } 19 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 59 | _ | _ | dB |

Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|-------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 40 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 2 | | V |
| Output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | _ | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25^{\circ}C$ | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | _ | - 0.4 | _ | mV/°C |
| Thermal protection operating temperature | $T_{j(TH)}$ | $I_O = 5 \text{ mA}$ | _ | 150 | | °C |

• AN7807NSP (7 V type)

The specified condition $T_j = 25$ °C means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, V_I = 12 V, I_O = 500 mA, C_I = 0.33 μF and C_O = 0.1 μF

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|---|-----|-----|-----|------|
| Output voltage | V _{O1} | $T_j = 25^{\circ}C$ | 6.7 | 7 | 7.3 | V |
| Output voltage tolerance | V _{O2} | $V_{\rm I} = 10 \text{ V to } 22 \text{ V}, I_{\rm O} = 5 \text{ mA to } 1 \text{ A}$ | 6.6 | _ | 7.4 | V |
| | | $T_j = 25^{\circ}C, P_D < 5 W$ | | | | |
| Line regulation 1 | REG_{IN1} | $V_I = 9.5 \text{ V to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$ | | 5 | 140 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 10 \text{ V to } 15 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 1.5 | 70 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 14 | 140 | mV |
| Load regulation 2 | REG _{L2} | $I_O = 250 \text{ mA to } 750 \text{ mA}, T_j = 25^{\circ}\text{C}$ | _ | 4.0 | 70 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 3.9 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 9.5 \text{ V to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.0 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 10 \text{ V to } 20 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 57 | _ | | dB |

· Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|-------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 46 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 2 | _ | V |
| Output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | _ | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25^{\circ}C$ | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | _ | - 0.5 | _ | mV/°C |
| Thermal protection operating temperature | T _{j(TH)} | $I_O = 5 \text{ mA}$ | _ | 150 | _ | °C |

• AN7808NSP (8 V type)

The specified condition $T_j = 25$ °C means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, V_I = 14 V, I_O = 500 mA, C_I = 0.33 μF and C_O = 0.1 μF

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|---|-----|-----|-----|------|
| Output voltage | V _{O1} | $T_j = 25^{\circ}C$ | 7.7 | 8 | 8.3 | V |
| Output voltage tolerance | V _{O2} | $V_{\rm I} = 11 \text{ V to } 23 \text{ V}, I_{\rm O} = 5 \text{ mA to } 1 \text{ A}$ | 7.6 | _ | 8.4 | V |
| | | $T_j = 25^{\circ}C, P_D < 5 W$ | | | | |
| Line regulation 1 | REG_{IN1} | $V_I = 10.5 \text{ V to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 6 | 160 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 11 \text{ V to } 17 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 2 | 80 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 12 | 160 | mV |
| Load regulation 2 | REG _{L2} | $I_O = 250 \text{ mA to } 750 \text{ mA}, T_j = 25^{\circ}\text{C}$ | _ | 4.0 | 80 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 3.9 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 10.5 \text{ V to } 25 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.0 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 11.5 \text{ V to } 21.5 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 56 | _ | _ | dB |

• Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|-------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 52 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | | 2 | | V |
| Output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25^{\circ}C$ | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | _ | - 0.5 | _ | mV/°C |
| Thermal protection operating temperature | $T_{j(TH)}$ | $I_O = 5 \text{ mA}$ | | 150 | | °C |

• AN7809NSP (9 V type)

The specified condition $T_j = 25$ °C means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, V_I = 15 V, I_O = 500 mA, C_I = 0.33 μF and C_O = 0.1 μF

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|---|------|-----|------|------|
| Output voltage | V _{O1} | $T_j = 25$ °C | 8.65 | 9 | 9.35 | V |
| Output voltage tolerance | V _{O2} | $V_{\rm I} = 12 \text{ V to } 24 \text{ V}, I_{\rm O} = 5 \text{ mA to } 1 \text{ A}$ | 8.55 | _ | 9.45 | V |
| | | $T_j = 25^{\circ}C, P_D < 5 W$ | | | | |
| Line regulation 1 | REG _{IN1} | $V_I = 11.5 \text{ V to } 26 \text{ V}, T_j = 25^{\circ}\text{C}$ | — | 7 | 180 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 12 \text{ V to } 18 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 2 | 90 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 12 | 180 | mV |
| Load regulation 2 | REG _{L2} | $I_O = 250 \text{ mA to } 750 \text{ mA}, T_j = 25^{\circ}\text{C}$ | _ | 4.0 | 90 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 3.9 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 11.5 \text{ V to } 26 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.0 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 11.5 \text{ V to } 21.5 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 56 | _ | _ | dB |

· Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|-------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 57 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 2 | _ | V |
| output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | _ | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25^{\circ}C$ | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | _ | - 0.5 | _ | mV/°C |
| Thermal protection operating temperature | T _{j(TH)} | $I_O = 5 \text{ mA}$ | | 150 | _ | °C |

• AN7810NSP (10 V type)

The specified condition $T_j = 25^{\circ}C$ means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, V_I = 16 V, I_O = 500 mA, C_I = 0.33 μF and C_O = 0.1 μF

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|---|-----|-----|------|------|
| Output voltage | V _{O1} | $T_j = 25^{\circ}C$ | 9.6 | 10 | 10.4 | V |
| Output voltage tolerance | V _{O2} | $V_{\rm I} = 13 \text{ V to } 25 \text{ V}, I_{\rm O} = 5 \text{ mA to } 1 \text{ A}$ | 9.5 | _ | 10.5 | V |
| | | $T_j = 25^{\circ}C, P_D < 5 W$ | | | | |
| Line regulation 1 | REG _{IN1} | $V_I = 12.5 \text{ V to } 27 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 8 | 200 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 13 \text{ V to } 19 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 2.5 | 100 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 12 | 200 | mV |
| Load regulation 2 | REG _{L2} | $I_O = 250 \text{ mA to } 750 \text{ mA}, T_j = 25^{\circ}\text{C}$ | _ | 4.0 | 100 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 3.9 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 12.5 \text{ V to } 27 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.0 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 13 \text{ V to } 23 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 56 | _ | | dB |

Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|-------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 56 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 2 | _ | V |
| Output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | _ | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25^{\circ}C$ | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | _ | - 0.6 | _ | mV/°C |
| Thermal protection operating temperature | T _{j(TH)} | $I_O = 5 \text{ mA}$ | _ | 150 | _ | °C |

• AN7812NSP (12 V type)

The specified condition $T_j = 25$ °C means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, V_I = 19 V, I_O = 500 mA, C_I = 0.33 μF and C_O = 0.1 μF

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|---|------|-----|------|------|
| Output voltage | V _{O1} | $T_j = 25^{\circ}C$ | 11.5 | 12 | 12.5 | V |
| Output voltage tolerance | V _{O2} | $V_{\rm I} = 15 \text{ V to } 27 \text{ V}, I_{\rm O} = 5 \text{ mA to } 1 \text{ A}$ | 11.4 | _ | 12.6 | V |
| | | $T_j = 25^{\circ}C, P_D < 5 W$ | | | | |
| Line regulation 1 | REG_{IN1} | $V_I = 14.5 \text{ V to } 30 \text{ V}, T_j = 25^{\circ}\text{C}$ | | 10 | 240 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 16 \text{ V to } 22 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 2 | 120 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 12 | 240 | mV |
| Load regulation 2 | REG _{L2} | $I_{O} = 250 \text{ mA to } 750 \text{ mA}, T_{j} = 25^{\circ}\text{C}$ | _ | 4.0 | 120 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 4.0 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 14.5 \text{ V to } 30 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.0 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 15 \text{ V to } 25 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 55 | _ | _ | dB |

Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|-------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 75 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 2 | _ | V |
| Output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | _ | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25^{\circ}C$ | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | _ | - 0.8 | _ | mV/°C |
| Thermal protection operating temperature | T _{j(TH)} | $I_O = 5 \text{ mA}$ | | 150 | _ | °C |

• AN7815NSP (15 V type)

The specified condition $T_j = 25^{\circ}C$ means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, V_I = 23 V, I_O = 500 mA, C_I = 0.33 μF and C_O = 0.1 μF

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|---|-------|-----|-------|------|
| Output voltage | V _{O1} | $T_j = 25^{\circ}C$ | 14.4 | 15 | 15.6 | V |
| Output voltage tolerance | V _{O2} | $V_{\rm I} = 18 \text{ V to } 30 \text{ V}, I_{\rm O} = 5 \text{ mA to } 1 \text{ A}$ | 14.25 | _ | 15.75 | V |
| | | $T_j = 25^{\circ}C, P_D < 5 W$ | | | | |
| Line regulation 1 | REG_{IN1} | $V_I = 17.5 \text{ V to } 30 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 11 | 300 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 20 \text{ V to } 26 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 3 | 150 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 12 | 300 | mV |
| Load regulation 2 | REG _{L2} | $I_O = 250 \text{ mA to } 750 \text{ mA}, T_j = 25^{\circ}\text{C}$ | _ | 4.0 | 150 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 4.0 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 17.5 \text{ V to } 30 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.0 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 18.5 \text{ V to } 28.5 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 54 | _ | _ | dB |

· Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 90 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | | 2 | | V |
| Output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | _ | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25^{\circ}C$ | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | _ | -1.0 | _ | mV/°C |
| Thermal protection operating temperature | $T_{j(TH)}$ | $I_O = 5 \text{ mA}$ | _ | 150 | | °C |

• AN7818NSP (18 V type)

The specified condition $T_j = 25$ °C means that the test should be carried out within so short a test time (within 10 ms) that the characteristic value drift due to the chip junction temperature rise can be ignored.

Unless otherwise specified, V_I = 27 V, I_O = 500 mA, C_I = 0.33 μF and C_O = 0.1 μF

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|-----------------------------------|-----------------------|---|------|-----|------|------|
| Output voltage | V _{O1} | $T_j = 25$ °C | 17.3 | 18 | 18.7 | V |
| Output voltage tolerance | V _{O2} | $V_I = 21 \text{ V to } 33 \text{ V}, I_O = 5 \text{ mA to } 1 \text{ A}$ | 17.1 | _ | 18.9 | V |
| | | $T_j = 25^{\circ}C, P_D < 5 W$ | | | | |
| Line regulation 1 | REG _{IN1} | $V_I = 21 \text{ V to } 33 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 14 | 360 | mV |
| Line regulation 2 | REG _{IN2} | $V_I = 24 \text{ V to } 30 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 4 | 180 | mV |
| Load regulation 1 | REG _{L1} | $I_O = 5 \text{ mA to } 1.5 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 14 | 360 | mV |
| Load regulation 2 | REG _{L2} | $I_O = 250 \text{ mA to } 750 \text{ mA}, T_j = 25^{\circ}\text{C}$ | _ | 4.0 | 180 | mV |
| Bias current | I _{Bias} | $T_j = 25^{\circ}C$ | _ | 4.1 | 8 | mA |
| Bias current fluctuation to input | $\Delta I_{Bias(IN)}$ | $V_I = 21 \text{ V to } 33 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | _ | 1.0 | mA |
| Bias current fluctuation to load | $\Delta I_{Bias(L)}$ | $I_{O} = 5 \text{ mA to } 1 \text{ A}, T_{j} = 25^{\circ}\text{C}$ | _ | _ | 0.5 | mA |
| Ripple rejection ratio | RR | $V_I = 22 \text{ V to } 32 \text{ V}, I_O = 100 \text{ mA}, f = 120 \text{ Hz}$ | 53 | _ | _ | dB |

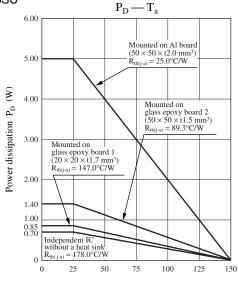
Design reference data

Note) The characteristics listed below are theoretical values based on the IC design and are not guaranteed.

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------------------|---|-----|------|-----|-------|
| Output noise voltage | V _{NO} | f = 10 Hz to 100 kHz | _ | 110 | _ | μV |
| Minimum input/output voltage difference | V _{DIF(min)} | $I_O = 1 \text{ A}, T_j = 25^{\circ}\text{C}$ | _ | 2 | _ | V |
| Output short-circuit current | I _{O(Short)} | $V_I = 35 \text{ V}, T_j = 25^{\circ}\text{C}$ | _ | 700 | _ | mA |
| Peak output current | I _{O(Peak)} | $T_j = 25^{\circ}C$ | _ | 2.0 | _ | A |
| Output voltage temperature coefficient | $\Delta V_{\rm O}$ / $T_{\rm a}$ | $I_O = 5 \text{ mA}, T_j = 0^{\circ}\text{C to } 125^{\circ}\text{C}$ | _ | -1.1 | _ | mV/°C |
| Thermal protection operating temperature | T _{j(TH)} | $I_O = 5 \text{ mA}$ | | 150 | _ | °C |

■ Application Notes

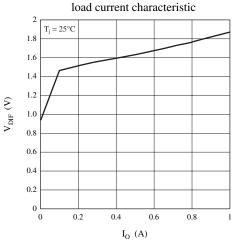
1. P_D — T_a curves of SP-3SU



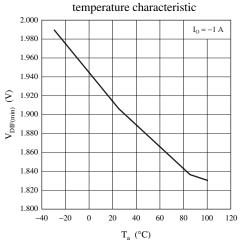
Ambient temperature T_a (°C)

2. Main Characteristics

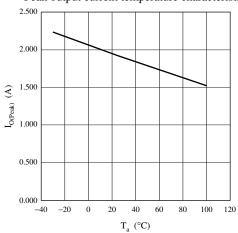
Minimum input/output voltage difference vs.



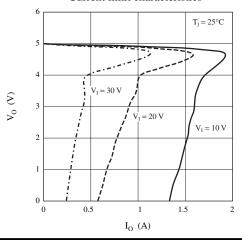
Minimum input/output voltage difference



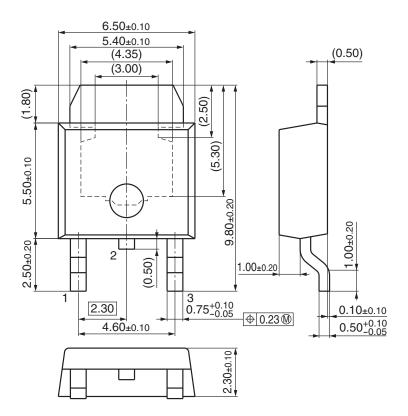




Current limit characteristics



- New Package Dimensions (Unit: mm)
- SP-3SUA (Lead-free package)



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